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John Colter, Netscape Navigator

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Results 1 - 10 of about 15,200 for **bytecode analysis method**. (0.76 seconds)

### JDC Tech Tips: August 29, 2000

... more work than the **concat2 method**, which makes ... optimizations that your **javap analysis** does not ... you need to supplement your **bytecode analysis** with performance ...  
[java.sun.com/developer/TechTips/2000/tt0829.html](http://java.sun.com/developer/TechTips/2000/tt0829.html) - 30k - [Cached](#) - [Similar pages](#)

### Citations: Java Architecture for **Bytecode Analysis** - Group, of ...

... so that it can determine the **method** that is ... The DejaVOO module implements the **analysis** algorithm described ... the Java Architecture for **Bytecode Analysis** (Jaba) [1 ...  
[citeseer.ist.psu.edu/context/1837773/0](http://citeseer.ist.psu.edu/context/1837773/0) - 6k - [Cached](#) - [Similar pages](#)

### Eye on performance: Micro performance benchmarking

... on performance, they dive into some **bytecode analysis** to try ... We need to examine the **bytecode** in the context ... **Method** int preIncement() 0 iconst\_0 1 istore\_0 2 ...  
[www-106.ibm.com/developerworks/library/j-perf12053.html?ca=dgr-Inxw09Microbenchmarking](http://www-106.ibm.com/developerworks/library/j-perf12053.html?ca=dgr-Inxw09Microbenchmarking) - 41k - [Cached](#) - [Similar pages](#)

### GroboUtils - Code Coverage Design (V2)

... **analysis** modules: parse the **bytecode methods** for all classes, mark **bytecode** instructions as under **analysis**, and generate data necessary for creating a report. ...  
[groboutils.sourceforge.net/codecoverage/v2\\_design.html](http://groboutils.sourceforge.net/codecoverage/v2_design.html) - 10k - [Cached](#) - [Similar pages](#)

### [PDF] BIT: **BYTECODE** INSTRUMENTING TOOL By HAN BOK LEE BS, University of ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)  
 ... BIT allows the user to insert calls to **analysis methods** anywhere in the **bytecode**, so that information can be extracted from the user program Page 4. ...  
[www-plan.cs.colorado.edu/hanlee/pubs/master.pdf](http://www-plan.cs.colorado.edu/hanlee/pubs/master.pdf) - [Similar pages](#)

### [PDF] Soot A Java **Bytecode** Optimization Framework

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 ... each **method** invocation has the correct number of arguments, arguments are well-typed) – **bytecode** verification • static : flow **analysis** for local type ...  
[www.cs.rutgers.edu/~ryder/oosem99/talks/isaila-soot.pdf](http://www.cs.rutgers.edu/~ryder/oosem99/talks/isaila-soot.pdf) - [Similar pages](#)

### BCEL - Byte Code Engineering Library (BCEL) v1

... When transforming code, for instance during optimization or when inserting **analysis method** calls, one typically searches for certain patterns of code to ...  
[www.cs.pdx.edu/~apt/cs577\\_2002/bcel-5.0rc1/docs/manual.html](http://www.cs.pdx.edu/~apt/cs577_2002/bcel-5.0rc1/docs/manual.html) - 91k - [Cached](#) - [Similar pages](#)

### [PDF] **Bytecode** Model Checking: An Experimental **Analysis**

File Format: PDF/Adobe Acrobat - [View as HTML](#)  
 ... Conventional **bytecode** verification works by abstracting a **method** to a state transition system and then computing a type of the **method** by dataflow **analysis**. ...  
[www.inf.ethz.ch/personal/basin/pubs/spin-bcv.pdf](http://www.inf.ethz.ch/personal/basin/pubs/spin-bcv.pdf) - [Similar pages](#)

### IRE-2001 - Accepted Papers

... require optimisation and **bytecode** for **methods** that do ... transfer delay (due to the incorporation of **bytecode**). ... Optimization by Utilizing Offline **Analysis** and the ...  
[www.cs.may.ie/~jpower/ire/papers.html](http://www.cs.may.ie/~jpower/ire/papers.html) - 8k - [Cached](#) - [Similar pages](#)

### Papers - USENIX Symposium on Internet Technologies and Systems ...

... In BIT, **analysis method** calls are inserted by using the **invokestatic bytecode** instruction and therefore, **analysis methods** have to be static. ...  
[www.usenix.org/publications/library/proceedings/usits97/full\\_papers/lee/lee\\_html/lee.html](http://www.usenix.org/publications/library/proceedings/usits97/full_papers/lee/lee_html/lee.html) - 54k - [Cached](#) - [Similar pages](#)



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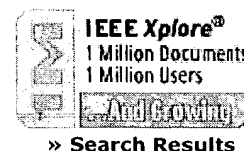
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*Onose, H.; Oikawa, S.; Yatsuo, T.; Kobayashi, Y.;*

Power Semiconductor Devices and ICs, 2000. Proceedings. The 12th International Symposium on , 22-25 May 2000

Pages:245 - 248

[Abstract] [PDF Full-Text (288 KB)] IEEE CNF

**2 Two-dimensional, finite Larmor radius magnetohydrodynamics code**

*Huba, J.D.;*

Plasma Science, 1996. IEEE Conference Record - Abstracts., 1996 IEEE International Conference on , 3-5 June 1996

Pages:200

[Abstract] [PDF Full-Text (92 KB)] IEEE CNF

**3 Backscatter theory and measurements for a millimeter-wave focused-beam radar**

*Blejer, D.J.; Irving, W.W.; Verbout, S.M.;*

Antennas and Propagation Society International Symposium, 1989. AP-S. Digest , 26-30 June 1989

Pages:1030 - 1033 vol.2

[Abstract] [PDF Full-Text (136 KB)] IEEE CNF

**4 Analysis of a complete 600 V-PT-IGBT structure using numerical device-simulation**

*Rudolf, R.; Netzel, M.; Shammas, N.Y.A.;*

Physical Modelling of Semiconductor Devices, IEE Colloquium on , 3 Apr 1995

Pages:9/1 - 9/6

[Abstract] [PDF Full-Text (368 KB)] IEEE CNF

**5 A general design methodology for the optimal multiple-field-limiting-**



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